From radical to triradical thin film processes: the Blatter radical derivatives.

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Figure S1. diNN-Blatter thin films C 1s and N 1s core-level spectra, as indicated, of a thin film not stoichiometrically correct, i.e., the evaporation was not successful as clearly seen from the intensity of the two features in the N 1s spectrum that show the same intensity. For the correct intensity see Figure 2.



Figure S2. diNN-Blatter XPS survey spectra: the comparison between the freshly evaporated and after annealing spectra, as indicated, is shown. After annealing at 493 K the N 1s signal disappears indicating that the molecule is desorbed.